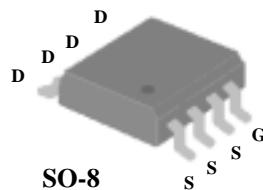


**P-CHANNEL ENHANCEMENT MODE
POWER MOSFET**

Simple drive requirement

Low on-resistance

Fast switching

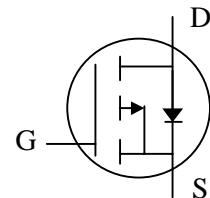


BV_{DSS}	-30V
$R_{DS(ON)}$	20mΩ
I_D	-8A

Description

Power MOSFETs from Silicon Standard provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SO-8 package is widely preferred for commercial and industrial surface mount applications and suited for low voltage applications such as DC/DC converters.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-30	V
V_{GS}	Gate-Source Voltage	± 25	V
$I_D @ T_A = 25^\circ C$	Continuous Drain Current ³	-8	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current ³	-6	A
I_{DM}	Pulsed Drain Current ^{1,2}	-50	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation	2.5	W
	Linear Derating Factor	0.02	W/°C
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Unit
R _{thj-amb}	Thermal Resistance Junction-ambient	Max.	50

Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

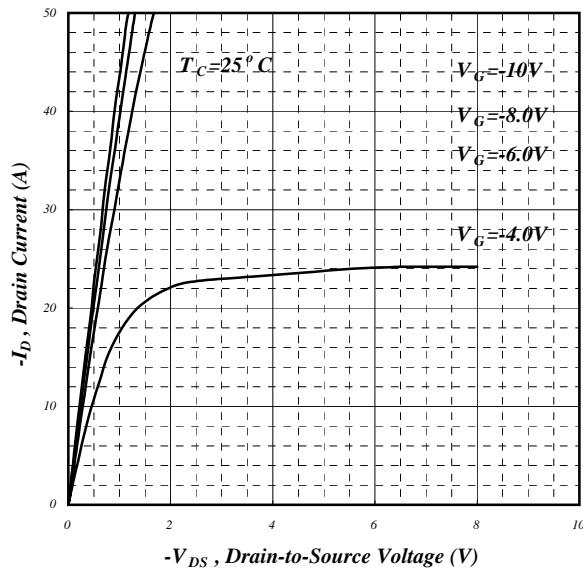
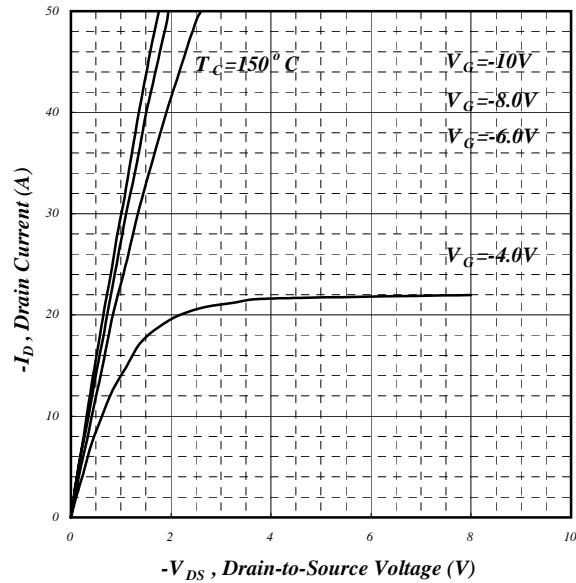
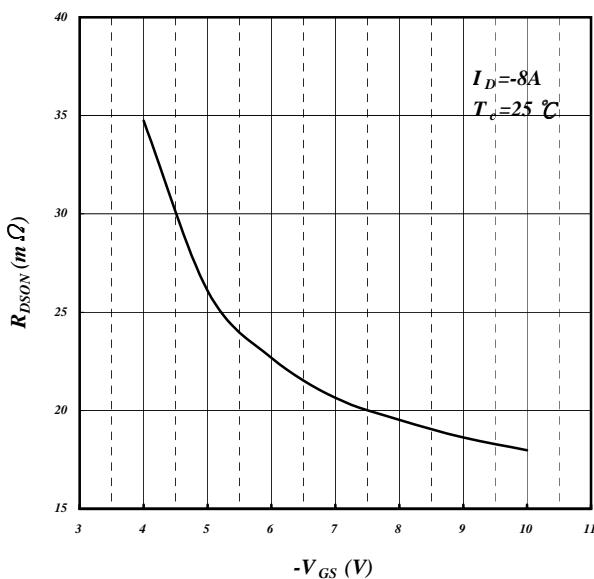
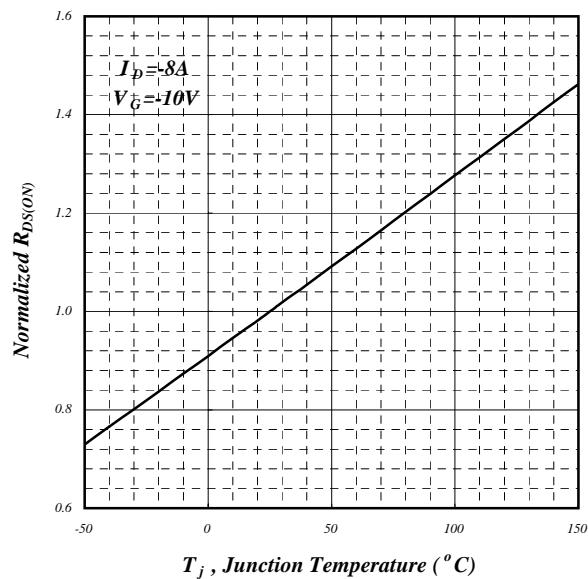
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{D}}=-250\mu\text{A}$	-30	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_{\text{D}}=-1\text{mA}$	-	-0.037	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance	$V_{\text{GS}}=-10\text{V}$, $I_{\text{D}}=-8\text{A}$	-	-	20	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}$, $I_{\text{D}}=-5\text{A}$	-	-	35	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{D}}=-250\mu\text{A}$	-1	-	-3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=-15\text{V}$, $I_{\text{D}}=-8\text{A}$	-	20	-	S
I_{DSS}	Drain-Source Leakage Current ($T_j=25^\circ\text{C}$)	$V_{\text{DS}}=-30\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	-1	uA
	Drain-Source Leakage Current ($T_j=70^\circ\text{C}$)	$V_{\text{DS}}=-24\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	-25	uA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 25$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_{\text{D}}=-4.6\text{A}$ $V_{\text{DS}}=-15\text{V}$ $V_{\text{GS}}=-10\text{V}$	-	36	-	nC
Q_{gs}	Gate-Source Charge		-	5.5	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge		-	3.5	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ²	$V_{\text{DS}}=-15\text{V}$ $I_{\text{D}}=-1\text{A}$ $R_G=6\Omega$, $V_{\text{GS}}=-10\text{V}$ $R_D=15\Omega$	-	12	-	ns
t_r	Rise Time		-	8	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time		-	75	-	ns
t_f	Fall Time		-	40	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$ $V_{\text{DS}}=-15\text{V}$ $f=1.0\text{MHz}$	-	1530	-	pF
C_{oss}	Output Capacitance		-	900	-	pF
C_{rss}	Reverse Transfer Capacitance		-	280	-	pF

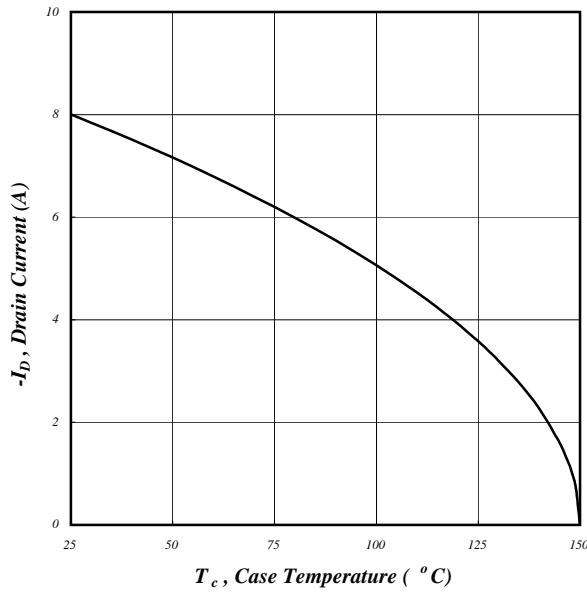
Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
I_s	Continuous Source Current (Body Diode)	$V_D=V_G=0\text{V}$, $V_S=-1.2\text{V}$	-	-	-2.1	A
I_{SM}	Pulsed Source Current (Body Diode) ¹		-	-	-50	A
V_{SD}	Forward On Voltage ²	$T_j=25^\circ\text{C}$, $I_s=-2.1\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-0.75	-1.2	V

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$.
- 3.Surface mounted on FR4 board, $t \leq 10$ sec.


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

Fig 3. On-Resistance v.s. Gate Voltage

Fig 4. Normalized On-Resistance v.s. Junction Temperature



**Fig 5. Maximum Drain Current v.s.
Case Temperature**

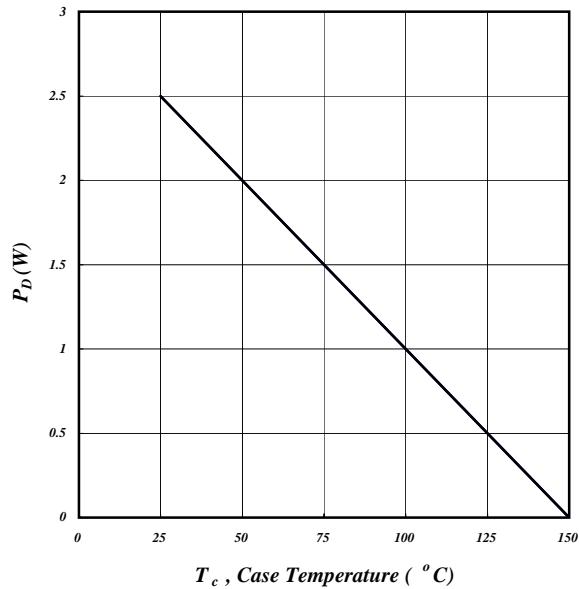


Fig 6. Typical Power Dissipation

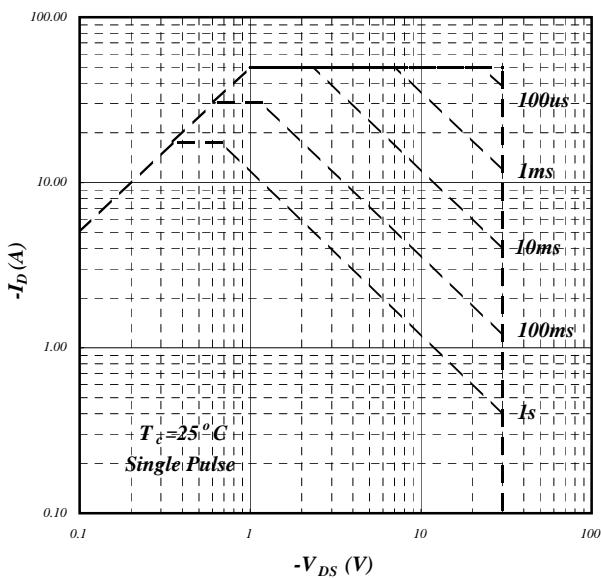


Fig 7. Maximum Safe Operating Area

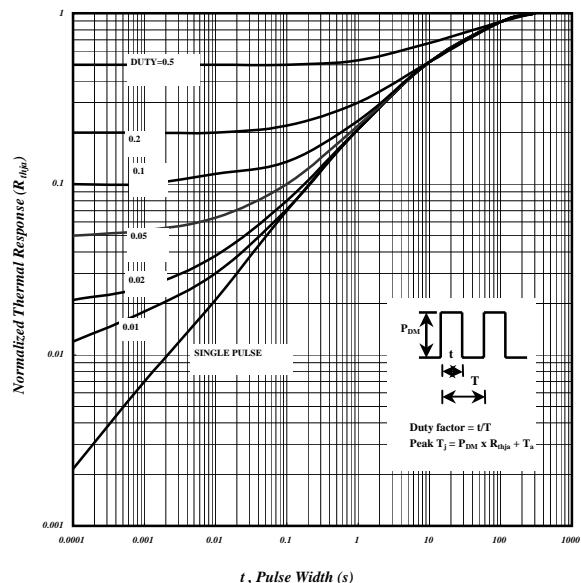
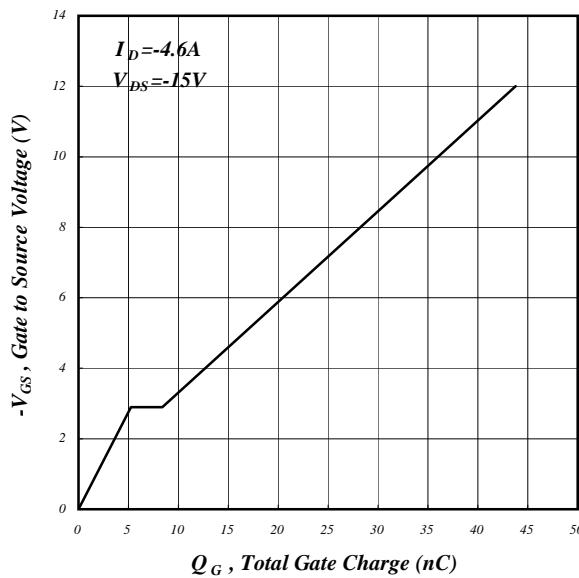
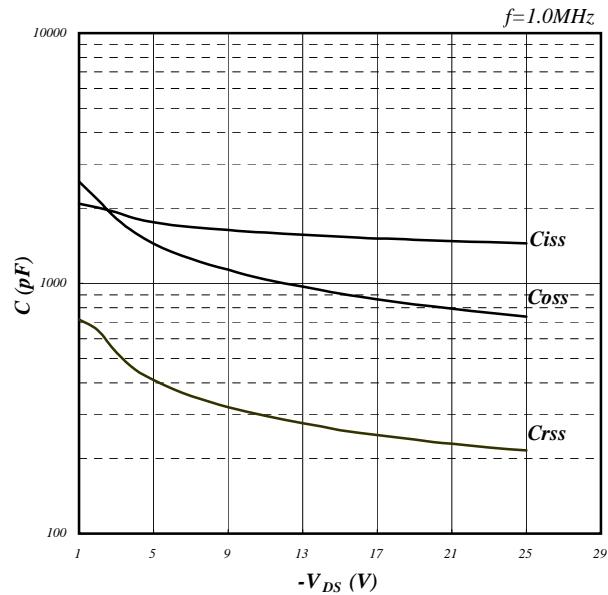
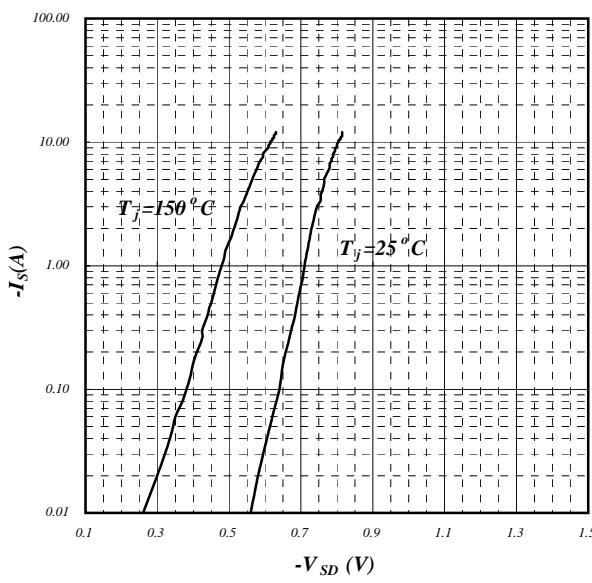
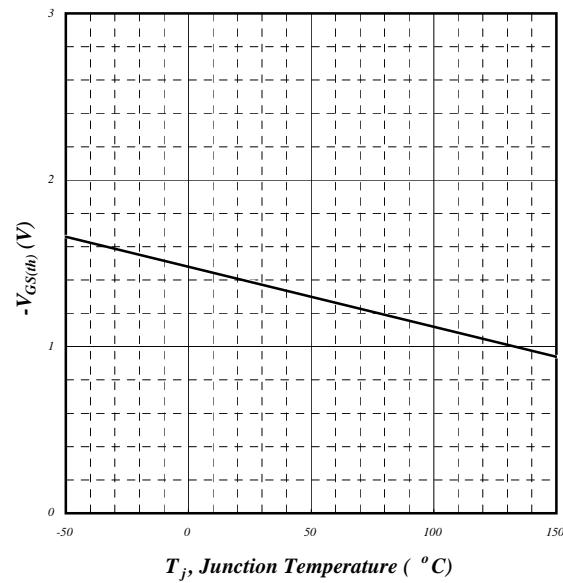
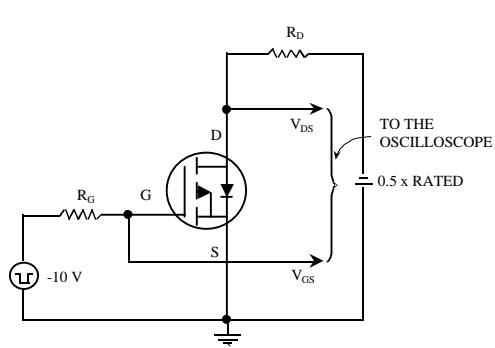
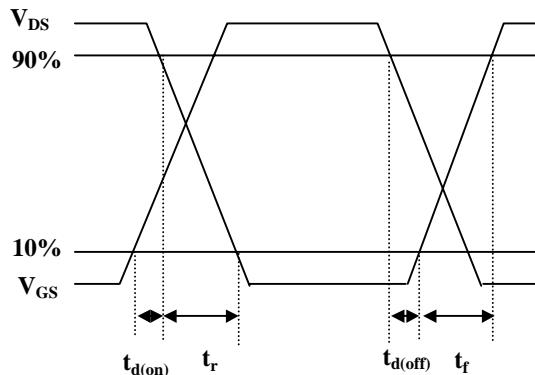
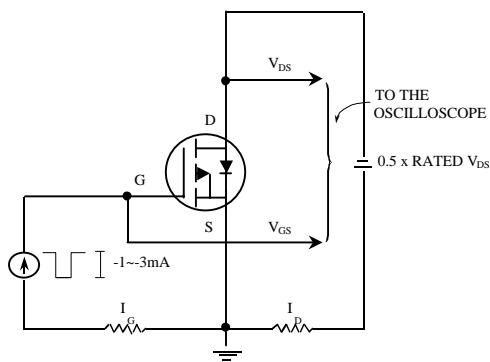
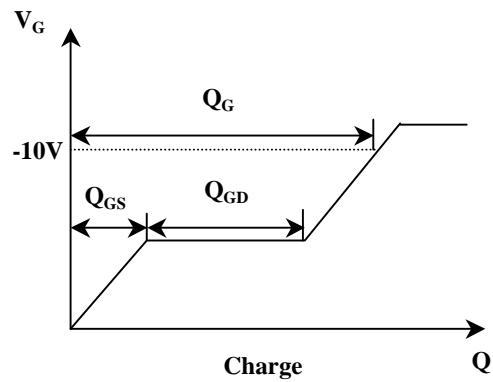


Fig 8. Effective Transient Thermal Impedance


Fig 9. Gate Charge Characteristics

Fig 10. Typical Capacitance Characteristics

Fig 11. Forward Characteristic of Reverse Diode

Fig 12. Gate Threshold Voltage v.s. Junction Temperature


Fig 13. Switching Time Circuit

Fig 14. Switching Time Waveform

Fig 15. Gate Charge Circuit

Fig 16. Gate Charge Waveform

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